



BSI Standards Publication

Semiconductor devices — Micro-electromechanical devices

Part 8: Strip bending test method for tensile
property measurement of thin films

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National foreword

This British Standard is the UK implementation of EN 62047-8:2011. It is identical to IEC 62047-8:2011.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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ISBN 978 0 580 60629 8

ICS 31.080.99

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 30 June 2011.

Amendments issued since publication

Amd. No.	Date	Text affected
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